



# TECHNICAL REPORT

BASIC EMC PUBLICATION

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**Electromagnetic compatibility (EMC) –  
Part 4-1: Testing and measurement techniques – Overview of the IEC 61000-4  
series**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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## CONTENTS

FOREWORD .....	3
INTRODUCTION .....	5
1 Scope and object.....	6
2 Normative references .....	6
3 Terms and definitions .....	9
4 General .....	10
5 Structure of the IEC 61000-4 series .....	11
6 Applicability of tests.....	11
7 Test report .....	18
Bibliography .....	19
Table 1 – Applicability of immunity tests based on location (environment).....	15
Table 2 – Applicability of immunity tests based on EUT ports .....	17

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTROMAGNETIC COMPATIBILITY (EMC) –****Part 4-1: Testing and measurement techniques –  
Overview of the IEC 61000-4 series**

## FOREWORD

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The main task of IEC technical committees is to prepare International Standards. However, a technical committee may propose the publication of a technical report when it has collected data of a different kind from that which is normally published as an International Standard, for example "state of the art".

IEC TR 61000-4-1, which is a technical report, has been prepared by IEC technical committee 77: Electromagnetic compatibility.

This Technical Report forms Part 4-1 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This first edition as a Technical Report cancels and replaces the third edition of the International Standard published in 2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) updates the text to include reference to the latest publications of the IEC 61000-4 series;
- b) gives more detailed assignment between applicable immunity tests and the electromagnetic environment in which equipment is intended to be used.

The text of this standard is based on the following documents:

Enquiry draft	Report on voting
77/498/DTR	77/508/RVC

Full information on the voting for the approval of this technical report can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61000 series, published under the general title *Electromagnetic compatibility (EMC)*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

## INTRODUCTION

IEC 61000 is published in several parts according to the following structure:

### **Part 1: General**

General consideration (introduction, fundamental principles)  
Definitions, terminology

### **Part 2: Environment**

Description of the environment  
Classification of the environment  
Compatibility levels

### **Part 3: Limits**

Emission limits  
Immunity test levels (in so far as they do not fall under the responsibility of the product committees)

### **Part 4: Testing and measurement techniques**

Measurement techniques  
Testing techniques

### **Part 5: Installation and mitigation guidelines**

Installation guidelines  
Mitigation methods and devices

### **Part 6: Generic standards**

### **Part 9: Miscellaneous**

Each part is further subdivided into several parts, published either as International Standards, technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and completed by a second number identifying the subdivision (example: 61000-6-1).

## **ELECTROMAGNETIC COMPATIBILITY (EMC) –**

### **Part 4-1: Testing and measurement techniques – Overview of the IEC 61000-4 series**

#### **1 Scope and object**

This part of IEC 61000 gives information and guidance on the EMC basic standards and other basic EMC documents published in the IEC 61000-4 series. Those basic standards describe mainly immunity tests to be considered and applied for electric and electronic equipment, including systems.

The object of this part of IEC 61000 is to give assistance to the technical committees of IEC or other bodies, users and manufacturers in

- considering the immunity test methods applicable to their products;
- determining the immunity test methods relevant for the electromagnetic environment in which their products are intended to be used;
- specifying the parts of their products being subjected to the relevant immunity test methods.

#### **2 Normative references**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161, *International Electrotechnical Vocabulary (IEV) – Part 161: Electromagnetic compatibility* (available at <<http://www.electropedia.org>>)

IEC TR 61000-1-1, *Electromagnetic compatibility (EMC) – Part 1: General – Section 1: Application and interpretation of fundamental definitions and terms*

IEC TR 61000-2-5, *Electromagnetic compatibility (EMC) – Part 2-5: Environment – Description and classification of electromagnetic environments*

IEC 61000-3-2, *Electromagnetic compatibility (EMC) – Part 3-2: Limits – Limits for harmonic current emissions (equipment input current  $\leq 16$  A per phase)*

IEC 61000-3-3, *Electromagnetic compatibility (EMC) – Part 3-3: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current  $\leq 16$  A per phase and not subject to conditional connection*

IEC TR 61000-3-4, *Electromagnetic compatibility (EMC) – Part 3-4: Limits – Limitation of emission of harmonic currents in low-voltage power supply systems for equipment with rated current greater than 16 A*

IEC TS 61000-3-5, *Electromagnetic compatibility (EMC) – Part 3-5: Limits – Limitation of voltage fluctuations and flicker in low-voltage power supply systems for equipment with rated current greater than 75 A*

IEC TR 61000-3-6, *Electromagnetic compatibility (EMC) – Part 3-6: Limits – Assessment of emission limits for the connection of distorting installations to MV, HV and EHV power systems*

IEC 61000-3-11, *Electromagnetic compatibility (EMC) – Part 3-11: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems – Equipment with rated current  $\leq 75$  A and subject to conditional connection*

IEC 61000-3-12, *Electromagnetic compatibility (EMC) – Part 3-12: Limits – Limits for harmonic currents produced by equipment connected to public low-voltage systems with input current  $> 16$  A and  $\leq 75$  A per phase*

IEC 61000-4-2, *Electromagnetic compatibility (EMC) – Part 4-2: Testing and measurement techniques – Electrostatic discharge immunity test*

IEC 61000-4-3, *Electromagnetic compatibility (EMC) – Part 4-3: Testing and measurement techniques – Radiated, radio-frequency, electromagnetic field immunity test*

IEC 61000-4-4, *Electromagnetic compatibility (EMC) – Part 4-4: Testing and measurement techniques – Electrical fast transient/burst immunity test*

IEC 61000-4-5, *Electromagnetic compatibility (EMC) – Part 4-5: Testing and measurement techniques – Surge immunity test*

IEC 61000-4-6, *Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields*

IEC 61000-4-7, *Electromagnetic compatibility (EMC) – Part 4-7: Testing and measurement techniques – General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto*

IEC 61000-4-8, *Electromagnetic compatibility (EMC) – Part 4-8: Testing and measurement techniques – Power frequency magnetic field immunity test*

IEC 61000-4-9, *Electromagnetic compatibility (EMC) – Part 4-9: Testing and measurement techniques – Pulse magnetic field immunity test*

IEC 61000-4-10, *Electromagnetic compatibility (EMC) – Part 4-10: Testing and measurement techniques – Damped oscillatory magnetic field immunity test*

IEC 61000-4-11, *Electromagnetic compatibility (EMC) – Part 4-11: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity tests*

IEC 61000-4-12, *Electromagnetic compatibility (EMC) – Part 4-12: Testing and measurement techniques – Ring wave immunity test*

IEC 61000-4-13, *Electromagnetic compatibility (EMC) – Part 4-13: Testing and measurement techniques – Harmonics and interharmonics including mains signalling at a.c. power port, low frequency immunity tests*

IEC 61000-4-14, *Electromagnetic compatibility (EMC) – Part 4-14: Testing and measurement techniques – Voltage fluctuation immunity test for equipment with input current not exceeding 16 A per phase*

IEC 61000-4-15, *Electromagnetic compatibility (EMC) – Part 4-15: Testing and measurement techniques – Flickermeter – Functional and design specifications 1*

IEC 61000-4-16, *Electromagnetic compatibility (EMC) – Part 4-16: Testing and measurement techniques – Test for immunity to conducted, common mode disturbances in the frequency range 0 Hz to 150 kHz*

IEC 61000-4-17, *Electromagnetic compatibility (EMC) – Part 4-17: Testing and measurement techniques – Ripple on d.c. input power port immunity test*

IEC 61000-4-18, *Electromagnetic Compatibility (EMC) – Part 4-18: Testing and measurement techniques – Damped oscillatory wave immunity test*

IEC 61000-4-19, *Electromagnetic Compatibility (EMC) – Part 4-19: Testing and measurement techniques – Test for immunity to conducted, differential mode disturbances and signalling in the frequency range 2 kHz to 150 kHz at a.c. power ports*

IEC 61000-4-20, *Electromagnetic compatibility (EMC) – Part 4-20: Testing and measurement techniques – Emission and immunity testing in transverse electromagnetic (TEM) waveguides*

IEC 61000-4-21, *Electromagnetic compatibility (EMC) – Part 4-21: Testing and measurement techniques – Reverberation chamber test methods*

IEC 61000-4-22, *Electromagnetic compatibility (EMC) – Part 4-22: Testing and measurement techniques – Radiated emissions and immunity measurements in fully anechoic rooms (FARs)*

IEC 61000-4-23, *Electromagnetic compatibility (EMC) – Part 4-23: Testing and measurement techniques – Test methods for protective devices for HEMP and other radiated disturbances*

IEC 61000-4-24, *Electromagnetic compatibility (EMC) – Part 4-24: Testing and measurement techniques – Test methods for protective devices for HEMP conducted disturbance*

IEC 61000-4-25, *Electromagnetic compatibility (EMC) – Part 4-25: Testing and measurement techniques – HEMP immunity test methods for equipment and systems*

IEC 61000-4-27, *Electromagnetic compatibility (EMC) – Part 4-27: Testing and measurement techniques – Unbalance, immunity test for equipment with input current not exceeding 16 A per phase*

IEC 61000-4-28, *Electromagnetic compatibility (EMC) – Part 4-28: Testing and measurement techniques – Variation of power frequency, immunity test for equipment with input current not exceeding 16 A per phase*

IEC 61000-4-29, *Electromagnetic compatibility (EMC) – Part 4-29: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests*

IEC 61000-4-30, *Electromagnetic compatibility (EMC) – Part 4-30: Testing and measurement techniques – Power quality measurement methods*

IEC TR 61000-4-32, *Electromagnetic compatibility (EMC) – Part 4-32: Testing and measurement techniques – High-altitude electromagnetic pulse (HEMP) simulator compendium*

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<sup>1</sup> Revision of IEC 60868.

IEC 61000-4-33, *Electromagnetic compatibility (EMC) – Part 4-33: Testing and measurement techniques – Measurement methods for high-power transient parameters*

IEC 61000-4-34, *Electromagnetic compatibility (EMC) – Part 4-34: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current more than 16 A per phase*

IEC TR 61000-4-35, *Electromagnetic compatibility (EMC) – Part 4-35: Testing and measurement techniques – HPEM simulator compendium*

IEC 61000-4-36, *Electromagnetic compatibility (EMC) – Part 4-36: Testing and measurement techniques – IEMI immunity test methods for equipment and systems*

IEC TR 61000-4-38, *Electromagnetic compatibility (EMC) – Part 4-38: Testing and measurement techniques – Test, verification and calibration protocol for voltage fluctuation and flicker compliance test systems*